

AD9244–SPECIFICATIONS

DC SPECIFICATIONS (AVDD = +5 V, CLKVDD = 3V, DRVDD = +3.0 V, $f_{\text{SAMPLE}} = 65 \text{ MSPS} (-65)$ or $40 \text{ MSPS} (-40)$, INPUT RANGE = 2V p-p, DIFFERENTIAL ANALOG INPUTS, DIFFERENTIAL CLOCK INPUTS, EXTERNAL REFERENCE, T_{MIN} to T_{MAX} unless otherwise noted)

Parameter	Temp	Test Level	AD9244BST-65			AD9244BST-40			Units
			Min	Typ	Max	Min	Typ	Max	
RESOLUTION	Full	VI	14			14			bits
DC ACCURACY									
No Missing Codes Guaranteed	Full	VI	14			14			bits
Offset Error	Full	VI							%FSR
Gain Error ¹	Full	VI							%FSR
Differential Nonlinearity (DNL) ²	Full	IV							LSB
	+25°C	I	±0.6			±0.6			LSB
Integral Nonlinearity (INL) ²	Full	IV							LSB
	+25°C	I	±1.9			±1.3			LSB
TEMPERATURE DRIFT									
Offset Error	Full	V							ppm/°C
Gain Error ¹	Full	V							ppm/°C
INTERNAL VOLTAGE REFERENCE									
Output Voltage Error (2V VREF)	Full	VI	±3.9			±3.9			mV
Load Regulation @ 1ma	Full	V							
Output Voltage Error (1V VREF)	Full	V	±2.79			±2.79			mV
Load Regulation @ 0.5ma	Full	V							
INPUT REFERRED NOISE									
VREF=2V	+25°C	V	0.82			0.79			LSB _{rms}
VREF=1V	+25°C	V							LSB _{rms}
ANALOG INPUT									
Input Voltage Range (differential)									
VREF=2V	+25°C	V	2			2			V p-p
VREF=1V	+25°C	V	1			1			V p-p
Common Mode Voltage	Full	V	0.5		2	0.5		2	V
Input Capacitance ³	+25°C	IV	7			7			pF
Input Bias Current	+25°C	IV	5			5			mA
Analog Bandwidth (full power)	+25°C	V	750			750			MHz
REFERENCE INPUT RESISTANCE	Full	V	5			5			kΩ
POWER SUPPLIES									
Supply Voltages									
AVDD	Full	IV	4.75	5.0	5.25	4.75	5.0	5.25	V
DRVDD	Full	IV	2.7	3.0	3.6	2.7	3.0	3.6	V
Supply Current									
IAVDD ²	Full	IV	104			62			mA
	+25°C	I							
IDRVDD ²	Full	IV	12			7.6			mA
	+25°C	I							
POWER CONSUMPTION									
DC Input ⁴	Full	V							mW
Sinewave Input ²	Full	VI	590			340			mW

NOTES

¹Gain Error is based on the ADC only (with a fixed 1.0V external reference).

²Measured at maximum clock rate, $f_{\text{IN}} = 2.4 \text{ MHz}$, full scale sinewave, with approximately 5pF loading on each output bit.

³Input capacitance refers to the effective capacitance between one differential input pin and AGND. Refer to Figure 2 for the equivalent analog input structure.

⁴Measured with dc input at maximum clock rate.

Specifications subject to change without notice

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AC SPECIFICATIONS (AVDD = +5 V, CLKVDD = 3V, DRVDD = +3.0V, $f_{\text{SAMPLE}} = 65 \text{ MSPS} (-65)$ or $40 \text{ MSPS} (-40)$, INPUT RANGE = 2Vp-p, DIFFERENTIAL ANALOG INPUTS, DIFFERENTIAL CLOCK INPUTS, EXTERNAL REFERENCE, T_{MIN} to T_{MAX} unless otherwise noted)

Parameter	Temp	Test Level	AD9244BST-65		AD9244BST-40		Units
			Min	Typ Max	Min	Typ Max	
SIGNAL TO NOISE RATIO $f_{\text{IN}} = 2.4 \text{ MHz}$	Full +25°C	VI					
		I	75		75		dBc
	+25°C	V	74		75		dBc
	+25°C	V	74				dBc
$f_{\text{IN}} = 100 \text{ MHz}$	+25°C	V	70		71		dBc
SIGNAL TO NOISE AND DISTORTION (SINAD) $f_{\text{IN}} = 2.4 \text{ MHz}$	Full +25°C	VI					
		I	74		75		dBc
	+25°C	V	72		74		dBc
	+25°C	V	73				dBc
$f_{\text{IN}} = 100 \text{ MHz}$	+25°C	V	70		70		dBc
TOTAL HARMONIC DISTORTION $f_{\text{IN}} = 2.4 \text{ MHz}$	Full +25°C	VI					
		I	-87		-92		dBc
	+25°C	V	-82		-82		dBc
	+25°C	V	-82				dBc
$f_{\text{IN}} = 100 \text{ MHz}$	+25°C	V	-80		-74		dBc
WORST OF 2nd, 3rd HARMONIC $f_{\text{IN}} = 2.5 \text{ MHz}$	Full	V	-90		-97		
		V	-83		-79		
	Full	V	-83				
	Full	V	-82		-77		
SPURIOUS FREE DYNAMIC RANGE $f_{\text{IN}} = 2.4 \text{ MHz}$	Full +25°C	VI					
		I	89		95		dBc
	+25°C	V	83		82		dBc
	+25°C	V	83				dBc
$f_{\text{IN}} = 100 \text{ MHz}$	+25°C	V	82		79		dBc

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DIGITAL SPECIFICATIONS (AVDD = +5V, DRVDD = +3.0V, f_{SAMPLE} = 65 MSPS, VREF = 2V, EXTERNAL REFERENCE, T_{MIN} to T_{MAX} unless otherwise noted)

Parameter	Temp	Test Level	AD9244BST-65		AD9244BST-40		Units
			Min	Typ Max	Min	Typ Max	
DIGITAL INPUTS (CLK+, CLK-, DFS, DUTY and OEB)							
Logic "1" Voltage	Full	IV	+2.0		+2.0		V
Logic "0" Voltage	Full	IV		+0.8		+0.8	V
Logic "1" Current	Full	IV		±10		±10	µa
Logic "0" Current	Full	IV		±10		±10	µa
Input Capacitance	+25°C	V	5		5		pf
DIGITAL OUTPUTS (DRVDD=5V) ¹							
Logic "1" Voltage (I _{OH} =50µa)	Full	IV	4.5		4.5		V
Logic "1" Voltage (I _{OH} =0.5ma)	Full	IV	2.4		2.4		V
Logic "0" Voltage (I _{OL} =1.6ma)	Full	IV		0.4		0.4	V
Logic "0" Voltage (I _{OL} =50µa)	Full	IV		0.1		0.1	V
DIGITAL OUTPUTS (DRVDD=3V) ¹							
Logic "1" Voltage (I _{OH} =50µa)	Full	IV	2.95		2.95		V
Logic "1" Voltage (I _{OH} =0.5ma)	Full	IV	2.80		2.80		V
Logic "0" Voltage (I _{OL} =50µa)	Full	IV		0.4		0.4	V
Logic "0" Voltage (I _{OL} =0.5ma)	Full	IV		0.05		0.05	V
Output Capacitance	+25°C	V	5		5		pf

NOTES

1. Output Voltage Levels measured with 5pF load on each output

Specifications subject to change without notice

SWITCHING SPECIFICATIONS (AVDD = +5V, DRVDD = +3.0V, T_{MIN} to T_{MAX} unless otherwise noted)

Parameter	Temp	Test Level	AD9244BST-65		AD9244BST-40		Units
			Min	Typ Max	Min	Typ Max	
CLOCK INPUT PARAMETERS							
Max Conversion Rate	Full	VI	65		40		MHz
Min Conversion Rate	Full	V		500		500	kHz
Clock Period ¹	Full	V	15.4		25		ns
Clock Pulsewidth High ²	Full	V	6.2		8.8		ns
Clock Pulsewidth Low ²	Full	V	6.2		8.8		ns
DATA OUTPUT PARAMETERS							
Output Delay (t _{OD}) ³	Full	V	3.5	7	3.5	7	ns
Pipeline Delay (Latency)	Full	V		8		8	Clock Cycles
Aperature Delay (t _A)	Full	V	3		3		ns
Aperature Uncertainty (Jitter)	Full	V		0.5		0.5	ps rms
Wake-Up Time ³	Full	V	2.5		2.5		ms
OUT OF RANGE RECOVERY TIME	Full	V	2		1		Clock Cycles

NOTES

¹ The clock period may be extended to 2µs with no degradation in specified performance at +25°C.² For the AD9244-65 only, with duty cycle stabilizer enabled. DCS function not applicable for -40 model.³ Output delay is measured from clock 50% transition to data 50% transition, with 5pF load on each output.⁴ Wake-up time is dependent on value of decoupling capacitors, typical values shown with 0.1µF and 10µF capacitors on REFT and REFB.

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AD9244-SPECIFICATIONS

ABSOLUTE MAXIMUM RATINGS*

Pin Name	WRT	Min	Max	Units
AVDD	AGND	-0.3	+6.5	V
DRVDD	DRGND	-0.3	+6.5	V
AGND	DRGND	-0.3	+0.3	V
AVDD	DRVDD	-6.5	+6.5	V
REFGND	AGND	-0.3	+0.3	V
CLK, DUTY	AGND	-0.3	AVDD+0.3	V
DFS	AGND	-0.3	AVDD+0.3	V
VIN+, VIN-	AGND	-0.3	AVDD+0.3	V
VREF	AGND	-0.3	AVDD+0.3	V
REFSENSE	AGND	-0.3	AVDD+0.3	V
REFB, REFT	AGND	-0.3	AVDD+0.3	V
CM LEVEL	AGND	-0.3	AVDD+0.3	V
VR	AGND	-0.3	AVDD+0.3	V
OTR	AGND	-0.3	AVDD+0.3	V
BIT0-BIT13	DRGND	-0.3	DRVDD+0.3	V
OEB	DRGND	-0.3	DRVDD+0.3	V
Digital Output Current			20	mA
Storage Temperature		-65	+150	°C
Operating Temperature			+175	°C
Case Temperature			+175	°C
Lead Temp. (10 sec)			+300	°C

EXPLANATION OF TEST LEVELS

Test Level

- I 100% production tested
- II 100% production tested at 25°C and sample tested at specified temperatures
- III Sample tested only
- IV Parameter is guaranteed by design and characterization testing
- V Parameter is a typical value only
- VI 100% production tested at 25°C; guaranteed by design and characterization testing for industrial temperature range; 100% production tested at temperature extremes for military devices.

*Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

ORDERING GUIDE

MODEL	TEMPERATURE RANGE	PACKAGE OPTION
AD9244BST-65,-40	-40°C to +85°C	ST-48
AD9244-EVAL		Evaluation Board

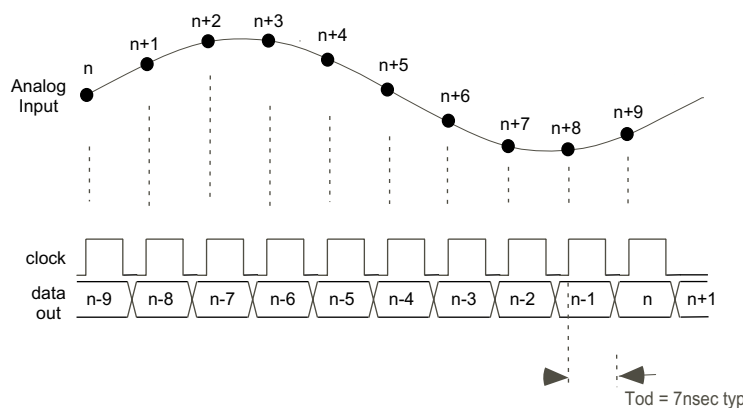


Figure 1. AD9244 Input Timing

CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although the AD9244 features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.

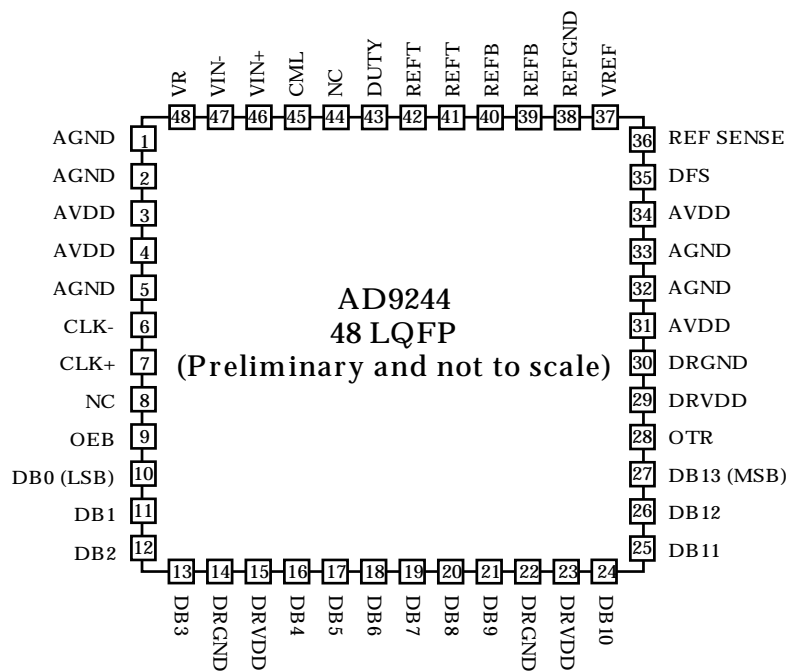
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AD9244-SPECIFICATIONS

PIN FUNCTION DESCRIPTIONS

Pin Number	Name	Descriptions
1,2,5,32,33	AGND	Analog Ground
3,4,31,34	AVDD	Analog Supply Voltage
5	CLKGND	Clock Ground
8,44	NC	Do not connect
7,6		CLK+,CLK- Differential Clock Input
9	OEB	Digital Output Enable (active low)
10	DB0 (LSB)	Least Significant Bit, digital output
11-13,16-21		
24-26	DB1 - DB12	Digital outputs
27	DB13 (MSB)	Most Significant Bit, digital output
14,22,30	DRGND	Digital Ground
15,23,29	DRVDD	Digital Supply Voltage
28	OTR	Out of range indicator (logic 1 indicates OTR)
35	DFS	Data Format Select, connect to; DRGND for straight binary DRVDD for 2's complement
36	REFSENSE	Internal reference control
37	VREF	Internal Reference
38	REFGND	Reference ground
39,40,41,42	REFT,REFB	Internal ADC reference decoupling
43	DUTY	50% Duty Cycle Restore, (Connect to AVDD to activate 50% duty cycle restore, de-couple to AGND for external control of both clock edges.)
45	CML	Common mode reference (0.5*AVDD)
46,47	VIN+,VIN-	Differential analog inputs
48	VR	Internal Bias Decoupling



AD9244–SPECIFICATIONS

DEFINITIONS OF SPECIFICATIONS

INTEGRAL NONLINEARITY (INL)

INL refers to the deviation of each individual code from a line drawn from “negative full scale” through “positive full scale.” The point used as “negative full scale” occurs 1/2 LSB before the first code transition. “Positive full scale” is defined as a level 1 1/2 LSB beyond the last code transition. The deviation is measured from the middle of each particular code to the true straight line.

DIFFERENTIAL NONLINEARITY (DNL, NO MISSING CODES)

An ideal ADC exhibits code transitions that are exactly 1 LSB apart. DNL is the deviation from this ideal value. Guaranteed no missing codes to 14-bit resolution indicates that all 16384 codes, respectively, must be present over all operating ranges.

ZERO ERROR

The major carry transition should occur for an analog value 1/2 LSB below $V_{IN+} = V_{IN-}$. Zero error is defined as the deviation of the actual transition from that point.

GAIN ERROR

The first code transition should occur at an analog value 1/2 LSB above negative full scale. The last transition should occur at an analog value 1 1/2 LSB below the nominal full scale. Gain error is the deviation of the actual difference between first and last code transitions and the ideal difference between first and last code transitions.

TEMPERATURE DRIFT

The temperature drift for zero error and gain error specifies the maximum change from the initial (+25°C) value to the value at T_{MIN} or T_{MAX} .

POWER SUPPLY REJECTION

The specification shows the maximum change in full scale from the value with the supply at the minimum limit to the value with the supply at its maximum limit.

APERTURE JITTER

The variation in aperture delay for successive samples which is manifested as noise on the input to the A/D.

APERTURE DELAY

Aperture delay is a measure of the sample-and-hold amplifier (SHA) performance and is measured from the rising edge of the clock input to when the input signal is held for conversion.

SIGNAL-TO-NOISE AND DISTORTION (S/N+D, SINAD) RATIO

The ratio of the rms value of the measured input signal to the rms sum of all other spectral components below the Nyquist frequency, including harmonics but excluding dc. The value for S/N+D is expressed in decibels.

EFFECTIVE NUMBER OF BITS (ENOB)

For a sine wave, SINAD can be expressed in terms of the number of bits. Using the following formula,

$$N = (SINAD - 1.76)/6.02$$

it is possible to get a measure of performance expressed as N , the effective number of bits.

Thus, effective number of bits for a device for sine wave inputs at a given input frequency can be calculated directly from its measured SINAD.

TOTAL HARMONIC DISTORTION (THD)

The ratio of the rms sum of the first six harmonic components to the rms value of the measured input signal and is expressed as a percentage or in decibels.

SIGNAL-TO-NOISE RATIO (SNR)

The ratio of the rms value of the measured input signal to the rms sum of all other spectral components below the Nyquist frequency, excluding the first six harmonics and dc. The value for SNR is expressed in decibels.

SPURIOUS FREE DYNAMIC RANGE (SFDR)

The difference in dB between the rms amplitude of the input signal and the peak spurious signal.

NYQUIST SAMPLING

When the frequency components of the analog input are below the Nyquist frequency ($F_{clock}/2$), this is often referred to as Nyquist sampling.

IF SAMPLING

Due to the effects of aliasing, an ADC is not necessarily limited to Nyquist sampling. Higher sampled frequencies will be aliased down into the 1st Nyquist zone ($DC - F_{clock}/2$) on the output of the ADC. Care must be taken that the bandwidth of the sampled signal does not overlap Nyquist zones and alias onto itself. Nyquist sampling performance is limited by the bandwidth of the input SHA and clock jitter (jitter adds more noise at higher input frequencies).

TYPICAL PERFORMANCE CHARACTERISTICS-AD9244

(AVDD = 5.0V, DRVDD = 3.0V, $f_{\text{SAMPLE}} = 65\text{MSPS}$ with CLK Duty Cycle Stabilizer Enabled, $T_A = 25^\circ\text{C}$, Differential Input Span, $V_{\text{CM}} = 2.5\text{V}$, $A_{\text{IN}} = -0.5\text{dBFS}$, $V_{\text{REF}} = 2.0\text{V}$, FFT length = 8K, unless otherwise noted)

TPC1. Single Tone 8K FFT, $f_{\text{IN}} = 5\text{MHz}$

TPC2. Single Tone SNR/SFDR vs A_{IN} , $f_{\text{IN}} = 5\text{MHz}$

TPC3. Single Tone 8K FFT, $f_{\text{IN}} = 31\text{MHz}$

TPC4. Dual-Tone SNR/SFDR vs A_{IN} with $f_{\text{IN1}} = 18\text{MHz}$ and $f_{\text{IN2}} = 20\text{MHz}$

TPC5. 3rd Order Intermodulation Distortion vs. $f_{\text{in1}}, f_{\text{in2}}$ at $A_{\text{in1}}, A_{\text{in2}} = -6.5\text{dBFS}$. Spacing between f_{in1} and $f_{\text{in2}} = 1\text{MHz}$.

TPC6. Single Tone SNR/SFDR vs A_{IN} , $f_{\text{IN}} = 31\text{MHz}$

TYPICAL PERFORMANCE CHARACTERISTICS-AD9244

(AVDD = 5.0V, DRVDD = 3.0V, $f_{\text{SAMPLE}} = 65\text{MSPS}$ with CLK Duty Cycle Stabilizer Enabled, $T_A = 25^\circ\text{C}$, Differential Input Span, VCM = 2.5V, AIN = -0.5dBFS, VREF = 2.0V, FFT length = 8K, unless otherwise noted)

TPC7. SINAD/ENOB vs. Frequency

TPC10. SNR vs. Frequency

TPC8. THD vs. Frequency

TPC11. SFDR vs. Frequency

TPC9. SNR vs. Temperature and Frequency

TPC12. THD vs. Temperature and Frequency

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TYPICAL PERFORMANCE CHARACTERISTICS-AD9244

(AVDD = 5.0V, DRVDD = 3.0V, $f_{\text{SAMPLE}} = 65\text{MSPS}$ with CLK Duty Cycle Stabilizer Enabled, $T_A = 25^\circ\text{C}$, Differential Input Span, $V_{\text{CM}} = 2.5\text{V}$, $A_{\text{IN}} = -0.5\text{dBFS}$, $V_{\text{REF}} = 2.0\text{V}$, FFT length = 8K, unless otherwise noted)

TPC13. Harmonics vs. Frequency

TPC16. SINAD vs. Sample Rate

TPC14. SFDR vs. Sample Rate

TPC17. SINAD/SFDR vs. Duty Cycle, $f_{\text{IN}} = 20\text{MHz}$

TPC15. Typical INL
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TPC18. Typical DNL

TYPICAL PERFORMANCE CHARACTERISTICS-AD9244

(AVDD = 5.0V, DRVDD = 3.0V, $f_{\text{SAMPLE}} = 65\text{MSPS}$ with CLK Duty Cycle Stabilizer Enabled, $T_A = 25^\circ\text{C}$, Differential Input Span, , VCM = 2.5V, AIN = -0.5dBFS, VREF = 2.0V, FFT length = 8K, unless otherwise noted)

TPC19. Dual-Tone 8K FFT, $f_{\text{IN1}} = 44.2\text{MHz}$ and $f_{\text{IN2}} = 45.6\text{MHz}$

TPC22. Dual Tone SNR and SFDR, $f_{\text{IN1}} = 44.2\text{MHz}$ and $f_{\text{IN2}} = 45.6\text{MHz}$

TPC20. Dual-Tone 8K FFT, $f_{\text{IN1}} = 69.2\text{MHz}$ and $f_{\text{IN2}} = 70.6\text{MHz}$

TPC23. Dual-Tone SNR and SFDR, $f_{\text{IN1}} = 69.2\text{MHz}$ and $f_{\text{IN2}} = 70.6\text{MHz}$

TPC21. Dual-Tone 8K FFT, $f_{\text{IN1}} = 139.2\text{MHz}$ and $f_{\text{IN2}} = 140.7\text{MHz}$

TPC24. Dual-Tone SNR and SFDR, $f_{\text{IN1}} = 139.2\text{MHz}$ and $f_{\text{IN2}} = 140.7\text{MHz}$

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TYPICAL PERFORMANCE CHARACTERISTICS-AD9244

(AVDD = 5.0V, DRVDD = 3.0V, $f_{\text{SAMPLE}} = 65\text{MSPS}$ with CLK Duty Cycle Stabilizer Enabled, $T_A = 25^\circ\text{C}$, Differential Input Span, , VCM = 2.5V, AIN = -0.5dBFS, VREF = 2.0V, FFT length = 8K, unless otherwise noted)

TPC25. Single Tone 8K FFT at IF = 190.82MHz
(typical WCDMA carrier), $f_{\text{SAMPLE}} = 61.44\text{MSPS}$

TPC28. Single Tone SNR and SFDR at IF = 190.82
MHz (typical WCDMA carrier), $f_{\text{SAMPLE}} = 61.44\text{MSPS}$

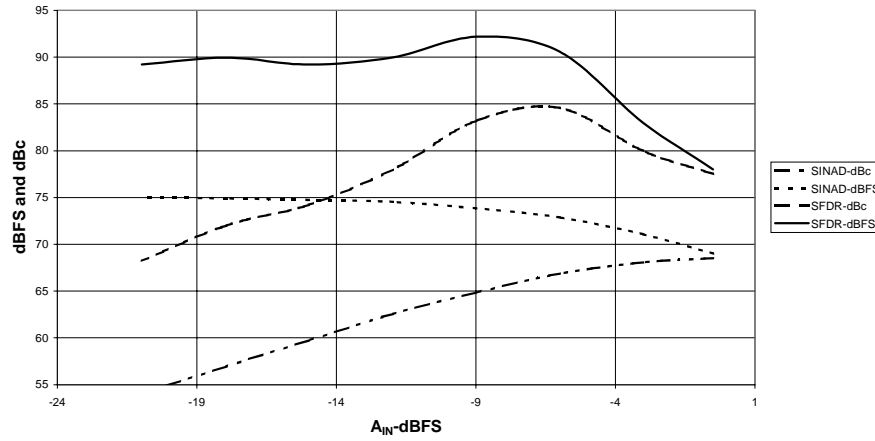
TPC26. Dual-Tone 8K FFT, $f_{\text{IN1}} = 239.1\text{MHz}$ and $f_{\text{IN2}} =$
240.7MHz

TPC29. Dual-Tone SNR and SFDR, $f_{\text{IN1}} = 239.1\text{MHz}$
and $f_{\text{IN2}} = 240.7\text{MHz}$

TPC27. CMRR vs. Frequency ($A_{\text{IN}} = 0\text{dBFS}$ and CML
= 2.5V

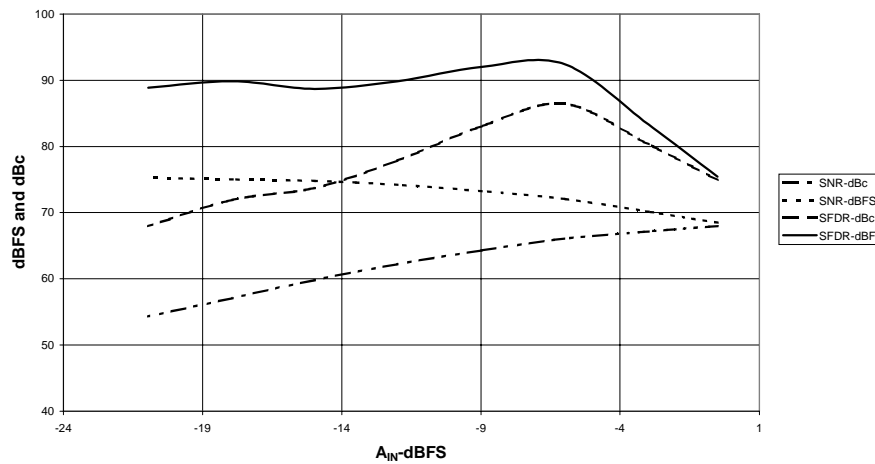
TYPICAL PERFORMANCE CHARACTERISTICS-AD9244

AD9244 - SINAD/SFDR vs. A_{IN} at $F_{IN}=190$ MHz



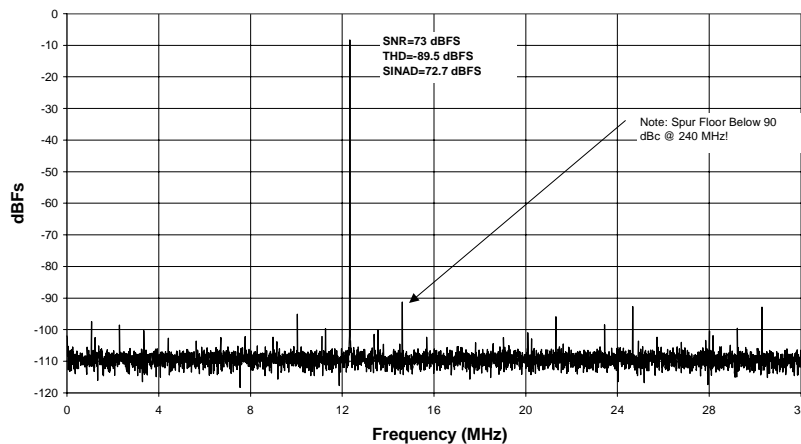
TPC30. Undersampling Performance of AD9244, $f_{CLK}=65$ MSPS, Driving ADC Inputs with Transformer and Balun

AD9244 - SNR/SFDR vs. A_{IN} at $F_{IN}=240$ MHz



TPC31. Undersampling Performance of AD9244, $f_{CLK}=65$ MSPS, Driving ADC Inputs with Transformer and Balun

AD9244 with $F_{IN}=240$ MHz and $F_{CLK}=65$ MSPS
(2 V Input Span-Differential, $A_{in}=-8.5$ dBFS)



TPC32. Undersampling Performance of AD9244, Driving ADC Inputs with Transformer and Balun

AD9244

THEORY OF OPERATION

The AD9244 is a high performance, single supply 14-bit ADC. In addition to high dynamic range Nyquist sampling, it is designed for excellent IF undersampling performance with an input analog bandwidth of 750MHz.

The AD9244 utilizes an eight stage pipeline architecture with a wideband, calibrated, input sample and hold amplifier (SHA) implemented on a cost-effective CMOS process. Each stage of the pipeline, excluding the last, consists of a low resolution flash ADC along with a switched capacitor DAC and interstage residue amplifier (MDAC). The MDAC amplifies the difference between the reconstructed DAC output and the flash input for the next stage in the pipeline. One bit of redundancy is used in each of the stages to facilitate digital correction of flash errors. The last stage simply consists of a flash ADC.

The performance of the AD9244 is greatly enhanced by the use of active calibration, yielding superb dynamic performance.

The pipeline architecture allows a greater throughput rate at the expense of pipeline delay or latency. While the converter captures a new input sample every clock cycle, it takes eight clock cycles for the conversion to be fully processed and appear at the output. This is illustrated in Figure 1 on page 5. This latency is not a concern in many applications. The digital output, together with the out-of-range indicator (OTR), is latched into an output buffer to drive the output pins. The output drivers of the AD9244 can be configured to interface with +5V or +3V logic families.

Connecting the DUTY pin to AVDD implements the internal clock stabilization function in the AD9244. In this mode, the AD9244 generates its own internal falling edge to create an internal 50% duty cycle clock, independent of the externally applied duty cycle. See the pin function descriptions on page 6 for details.

If the DUTY pin is connected to ground through a 10KΩ resistor or left floating (and decoupled), the AD9244 will use both edges of the external clock in its internal timing circuitry (see Figure 1 and specification page for exact timing requirements).

Control of straight binary or two's complement output format is accomplished with the DFS pin. See the pin function descriptions on page 6 for details.

The ADC samples the analog input on the rising edge of the clock. While clock is low, the input SHA is in sample mode. When the clock transitions to a high logic level, the SHA goes into the hold mode. System disturbances just prior to or immediately after the rising edge of the clock and/or excessive clock jitter may cause the input SHA to acquire the wrong value, and should be minimized.

ANALOG INPUT OPERATION

Figure 2 shows the equivalent analog input of the AD9244 which consists of a 750 MHz differential SHA. The differential input structure of the SHA is flexible, allowing the device to be configured for either a differential or single-ended input. The analog inputs VIN+ and VIN- are interchangeable, with the exception that reversing the

inputs to the VIN+ and VIN- pins results in a data inversion (complementing the output word).

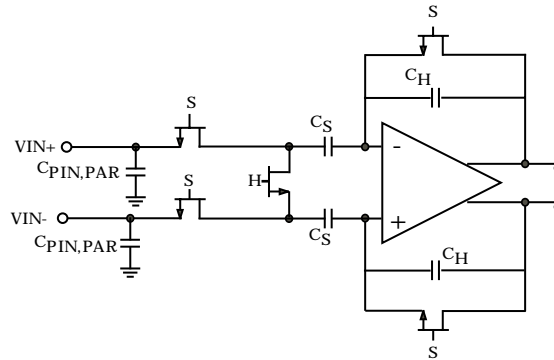


Figure 2. Analog Input of AD9244 SHA

The optimum noise and dc linearity performance for either differential or single-ended inputs is achieved with the largest input signal voltage span (i.e., 2V input span) and matched input impedance for VIN+ and VIN-. Only a slight degradation in dc linearity performance exists between the 2V and 1V input spans.

High frequency inputs may find the 1V span better suited to achieve superior SFDR performance. (See Typical Performance Characteristics.)

When the ADC is driven by an op amp and a capacitive load is switched onto the output of the op amp, the output will momentarily drop due to its effective output impedance. As the output recovers, ringing may occur. To remedy the situation, a series resistor can be inserted between the op amp and the SHA input as shown in Figure 3. A shunt capacitance also acts like a charge reservoir, sinking or sourcing the additional charge required by the hold capacitor, CH, further reducing current transients seen at the op amp's output.

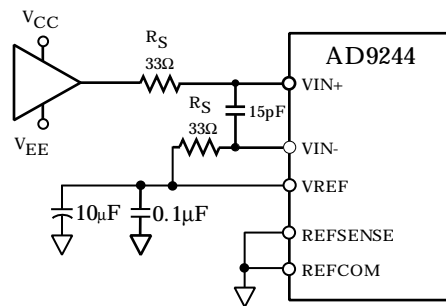


Figure 3. Resistors Isolating SHA Input from Op Amp

The optimum size of this resistor is dependent on several factors, including the ADC sampling rate, the selected op amp, and the particular application. In most applications, a 30Ω to 100Ω resistor is sufficient.

For noise sensitive applications, the very high bandwidth of the AD9244 may be detrimental and the addition of a series resistor and/or shunt capacitor can help limit the wideband noise at the ADC's input by forming a low pass filter. The source impedance driving VIN+ and VIN- should be matched. Failure to provide matching may result in degradation of the SNR, THD, or SFDR of the AD9244.

ANALOG INPUT AND REFERENCE OVERVIEW

The differential input span of the AD9244 is equal to the potential at the VREF pin. The VREF potential may be obtained from the internal AD9244 reference or an external source.

In differential applications, the center point of the input span is obtained by the common mode level of the signals. In single ended applications, the center point is the dc potential applied to one input pin while the signal is applied to the opposite input pin.

Figure 4 is a simplified model of the AD9244 analog input, showing the relationship between the analog inputs, VIN+, VIN-, and the reference voltage, VREF. Note that this is only a symbolic model and that no actual negative voltages exist inside the AD9244. Similar to the voltages applied to the top and bottom of the resistor ladder in a flash ADC, the value VREF/2 defines the minimum and maximum input voltages to the ADC core.

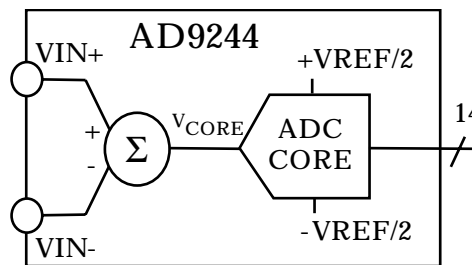


Figure 4. Equivalent Analog Input of AD9244

The addition of a differential input structure allows the user to easily configure the inputs for either single-ended or differential operation. The ADC's input structure allows the dc offset of the input signal to be varied independently of the input span of the converter. Specifically, the input to the ADC core can be defined as the difference of the voltages applied at the VIN+ and VIN- input pins. Therefore, the equation

$$V_{CORE} = VIN+ - VIN- \tag{1}$$

defines the output of the differential input stage and provides the input to the ADC core.

The voltage, V_CORE, must satisfy the condition,

$$-VREF/2 < V_{CORE} < VREF/2 \tag{2}$$

where VREF is the voltage at the VREF pin.

Table I. Analog Input Configuration Summary

Input Connection	Coupling	Input Span (V)	Input Range (V)		Comments
			VIN+ ¹	VIN- ¹	
Single-Ended	DC or AC	1.0	0.5 to 1.5	1.0	Best for stepped input response applications, requires ±5 V op amp.
		2.0	1 to 3	2.0	Optimum noise performance for single ended mode, often requires low distortion op amp with VCC > +5 V due to its head-room issues.
Differential (via Transformer) or Amplifier	DC or AC	1.0	2.25 to 2.75	2.75 to 2.25	Optimum full-scale THD and SFDR performance well beyond the ADC's Nyquist frequency. Preferred mode for undersampling applications.
		2.0	2.0 to 3.0	3.0 to 2.0	Optimum noise performance for differential mode.

NOTE

¹VIN+ and VIN- can be interchanged if signal inversion is required.

Table II. Reference Configuration Summary

Reference Operating Mode	Input Span (VIN+-VIN-) (V p-p)	Required VREF (V)	Connect	To
INTERNAL	1	1	REFSENSE	VREF
INTERNAL	2	2	REFSENSE	AGND
INTERNAL	1 ≤ SPAN ≤ 2 (SPAN=VREF)	1 ≤ VREF ≤ 2.0 VREF = (1 + R1/R2)	R1 R2	VREF AND REFSENSE REFSENSE AND REFGND
EXTERNAL	SPAN=EXTERNAL REF	1 ≤ VREF ≤ 2.0	REFSENSE VREF	AVDD EXTERNAL REF

OUTLINE DIMENSIONS
 Dimensions shown in inches and (mm).

**48 pin LQFP package
 (ST-48)**

